

Specification for Approval

Date: 2014/07/14

東莞台慶 Customer:

TAI-TECH P/N:

FPI0503F-Series

	CUSTOMER	R P/N:								
	DESCRIPTI	ON:								
	QUANTITY	:						pcs	<u>3</u>	
										_
REM	IARK:									
		Cu	stom	er A	ppro	oval	Fee	edba	ack	
		北 宮	in in its	₹ \$1.	坩	胚	份		限公司	

TAI-TECH Advanced Electronics Co., Ltd

□ 西北臺慶科技股份有限公司

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Mike Yang	Jack Chan	Shelly Hsu

BFPI5530330M00 TA734003

SMD Type Power Inductors

FPI0503F-Series

	ECN HISTORY LIST							
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN			
1.0	14/07/14	新 發 行	楊祥忠	詹偉特	徐允珮			
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SMD Type Power Inductors

FPI0503F-Series

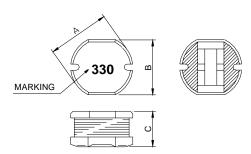
1. Features

- 1.Excellent solderability and high heat resistance.
- 2.Excellent terminal strength construction.
- 3. Packed in embossed carrier tape and can be used by automatic mounting machine.
- 4.100% Lead(Pb) & Halogen-Free and RoHS compliant.





2. Dimension



Size	A(mm)	B(mm)	C(mm)
FPI 0503F	5.80±0.3	5.20±0.3	3.00±0.3

Unit: mm

3. Part Numbering



A: Series B: Dimension

C: Lead free type

D: Inductance 330=33.0uH
E: Inductance Tolerance M=±20%

4. Specification

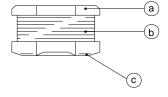
TAI-TECH	Induc	tance (uH)	DCR	Isat	Irms	
Part Number	Tolerance	Test Frequency (Hz)	$(m\Omega)$ max.	(A) max.	(A) max.	
FPI0503F-1R0M	1.00±20%	1V/100K	30	4.50	4.50	
FPI0503F-1R8M	1.80±20%	1V/7.96M	50	4.00	2.80	
FPI0503F-4R7M	4.70±20%	1V/7.96M	70	2.70	2.70	
FPI0503F-6R8M	6.80±20%	1V/7.96M	71.2	1.87	1.87	
FPI0503F-8R2M	8.20±20%	1V/7.96M	100	2.00	2.00	
FPI0503F-100M	10.0±20%	1V/2.52M	200	1.90	1.90	
FPI0503F-330M	33.0±20%	1V/2.52M	450	1.40	1.40	

Note

For the parts with inductance under 82 uH, the L is measured at 1MHz then when a lsat current is applied, the L should drop less than 35%. For the parts with inductance over 100 uH, the L is measured at 1KHz then when a lsat current is applied, the L should drop less than 35%.

For all FPI series ,when a Irms current is applied, the temperature rised of the parts is less than 40 degree C

5. Material List



No.	Item	Material
1	Core	Ferrite DR Core
2	Wire	Enamelled Copper wire
3	Terminal	Ag+Ni+Sn

6. Schematic Diagram

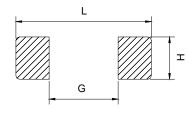


7. Reliability and Test Condition

Item	Performance	Test Condition				
Operating Temperature	-25~+85℃					
Storage temperature	-25~+85℃					
Rated Current	Base on temp. rise & △L/LOA≦35%					
Temperature Rise Test	Δt ≦40 °C					
Life Test		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles) Temperature: 125±2°C (Bead) Temperature: 85±2°C (Inductor) Applied current: rated current Duration: 1000±12hrs				
Load Humidity		Measured at room temperature after placing for 24±2 hrs Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Humidity: 85±2 % R.H, Temperature: 85℃±2℃ Duration: 1000hrs Min. with 100% rated current Measured at room temperature after placing for 24±2 hrs Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1: -40±2℃ 30±5min Step2: 25±2℃ ≤0.5min Step3: 105±2℃ 30±5min Number of cycles: 500 Measured at room temperature after placing for 24±2 hrs				
Thermal shock						
Vibration	Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within±15% of initial value and shall not exceed the specification value	Oscillation Frequency: 10~2K~10Hz for 20 minutes Equipment: Vibration checker Total Amplitude:1.52mm±10% Testing Time: 12 hours(20 minutes, 12 cycles each of 3 orientations) °				
Shock		Type				
Bending		Shall be mounted on a FR4 substrate of the following dimensions: >=0805:40x100x1.2mm <0805:40x100x0.8mm Bending depth: >=0805:1.2mm <0805:0.8mm duration of 10 sec.				
Soderability	More than 95% of the terminal electrode should be covered with solder °					

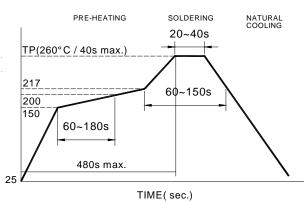
Item	Item Performance Test Condition			
Resistance to Soldering Heat		Number of heat cycles: 1 Temperature (°C) Time(s) Temperature ramp/immersion and emersion rate		
		260 ±5(solder temp) 10 ±1 25mm/s ±6 mm/s		
Terminal Strength	Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a force (>0805:1kg, <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested.		

8. Recommended PC Board Pattern



L(mm)	G(mm)	H(mm)
6.0	1.7	5.5

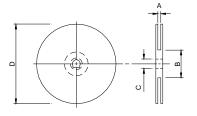
Reflow Soldering

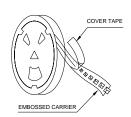


Reflow times: 3 times max.

9. Packaging Information

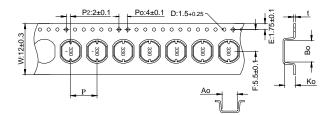
9-1. Reel Dimension





Туре	A(mm)	B(mm)	C(mm)	D(mm)
13"x12mm	14 ⁺⁰	100 ⁻⁰	13±0.5	330

9-2.1 Tape Dimension / 12mm

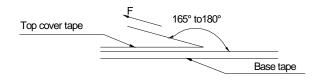


Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)
0503	6.0±0.1	5.7±0.1	3.3±0.1	8.0±0.1	0.35±0.05

9-3. Packaging Quantity

Size	0503
Chip / Reel	2000
Inner box	8000
Carton	32000

9-4. Tearing Off Force



The force for tearing off cover tape is 5 to 120 grams in the arrow direction under the following conditions.

Room Temp.	Room Humidity	Room atm	Tearing Speed	
(℃)	(%)	(hPa)	mm/min	
5~35	45~85	860~1060	300	

Application Notice

• Storage Conditions (component level)

To maintain the solderability of terminal electrodes:

- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



Test Report

號碼(No.): CE/2014/60591 日期(Date): 2014/06/12 頁數(Page): 1 of 11

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(東莞臺慶精密電子有限公司 / TAI-TECH ADVANCED ELECTRONICS (DONGGUAN) CO. LTD.)

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑚科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

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(廣東省東莞市黄江鎭黄牛埔福祥街2號 / NO. 2, FUXIANG STREET, HUANGNIUPU, HUANGJIANG TOWN, DONGGUAN, GUANGDONG) (江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (桃園縣中壢市中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)

: WINDING POWER INDUCTOR/SMD POWER INDUCTOR

樣品型號(Style/Item No.)

: LQN, LQC, FPI, FPIG, FPIP SERIES

收件日期(Sample Receiving Date)

: 2014/06/04

測試期間(Testing Period)

: 2014/06/04 TO 2014/06/11

測試結果(Test Results) : 請見下一頁 (Please refer to next pages).



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測試結果(Test Results)

測試部位(PART NAME)No.1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鎬 / Cadmium (Cd)	mg/kg	参考IEC 62321-5: 2013方法, 以感應耦合 電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	多考IEC 62321-5: 2013方法, 以感應耦合 電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	多考IEC 62321-4: 2013方法, 以感應耦合 電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.
六價络 / Hexavalent Chromium Cr(VI)	mg/kg	参考IEC 62321: 2008方法,以UV-VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
六溴環十二烷及所有主要被辨别出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α - HBCDD, β - HBCDD, γ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321: 2008方法,以氣相層析/質 譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鄰苯二甲酸甲苯基丁酯 / BBP (Benzyl butyl phthalate) (CAS No.: 85-68-7)	%	参考EN 14372, 以氣相層析/質譜儀檢測./ With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二 (2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	%	参考EN 14372, 以氣相層析/質譜儀檢測./ With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761-40-0; 68515-49-1)	%	参考EN 14372, 以氣相層析/質譜儀檢測./ With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553-12-0; 68515-48-0)	%	參考EN 14372, 以氣相層析/質譜儀檢測./ With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n- octyl phthalate) (CAS No.: 117-84- 0)	%	参考EN 14372, 以氣相層析/質譜儀檢測./ With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)		参考EN 14372, 以氣相層析/質譜儀檢測./ With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異丁酯 / DIBP (Di- isobutyl phthalate) (CAS No.: 84- 69-5)	1	參考EN 14372, 以氣相層析/質譜儀檢測。/ With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
多溴聯苯總和 / Sum of PBBs	mg/kg			n.d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n.d.
二溴聯苯 / Dibromobiphenyl	mg/kg	- -	5	n.d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n.d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n.d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n.d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n.d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n.d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n.d.
九溴聯苯 / Nonabromobiphenyl	mg/kg		5	n.d.
十溴聯苯 / Decabromobiphenyl	mg/kg	参考IEC 62321: 2008方法,以氣相層析/質 譜儀檢測。/ With reference to IEC 62321: 2008 and performed by GC/MS.	5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg		-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n.d.
へ溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg		5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg		5	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鹵素 / Halogen			,	10.1
鹵素 (氣) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	参考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(氣)/ Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg		50	n.d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n.d.
鹵素(碘)/ Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n.d.

備註(Note):

- 1. mg/kg = ppm; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. "-" = Not Regulated (無規格値)
- 5. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)



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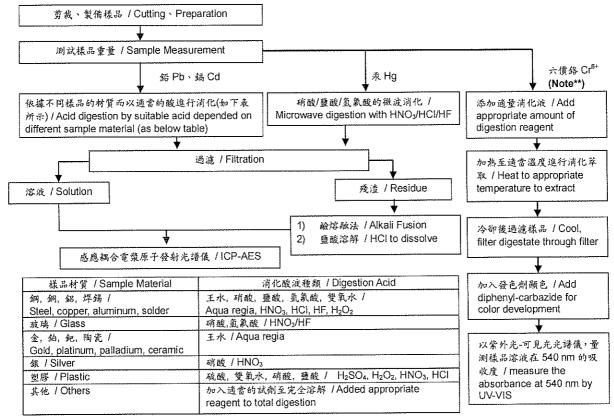
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- 1) 根據以下的流程圖之條件,樣品已完全溶解。(六價格測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr6+ test method excluded)
- 測試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



Note** (For IEC 62321)

- (1) 針對非金屬材料加入鹼性消化液,加熱至 90~95℃萃取. / For non-metallic material, add alkaline digestion reagent and heat to 90~95°C
- (2) 針對金屬材料加入純水,加熱至沸騰萃取. / For metallic material, add pure water and heat to boiling.

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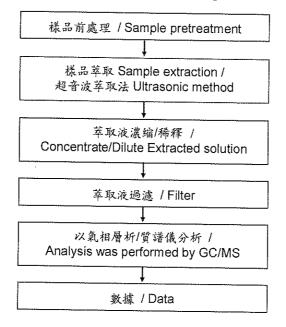
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六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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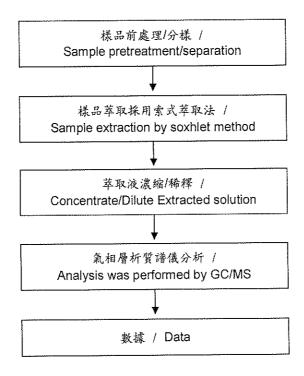
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可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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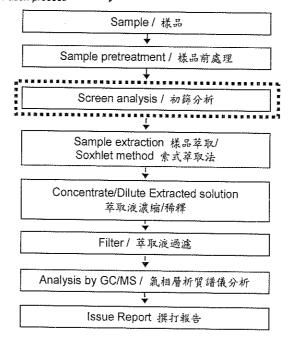
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多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong

確認程序 / Confirmation process - - - →



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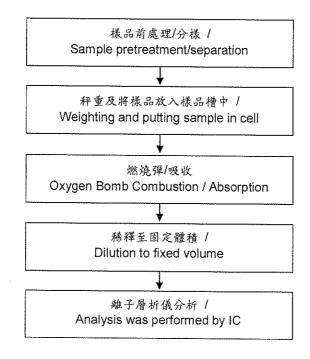
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鹵素分析流程圖 / Analytical flow chart of halogen content

- 测試人員:陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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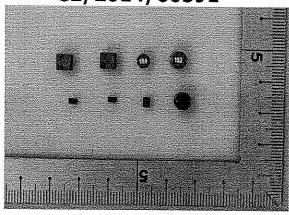
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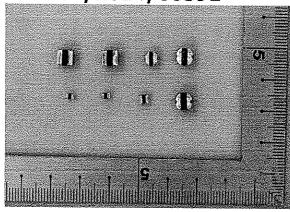
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(The tested sample / part is marked by an arrow if it's shown on the photo.)

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